

Description

The PUMA67E4001/A is a 4Mbit CMOS EEPROM module in a JEDEC 68 pin J leaded Ceramic Surface Mount Substrate. Access times of 120, 150, 170 and 200ns are available. The output width is user configurable as 8, 16, or 32 bits wide using CS1-4 and is available in two pinout options, single WE or WE1-4 (version /A). Page write (128 bytes) is performed in 5 ms (typical). The device also features both hardware and software data protection with DATA polling and Toggle bit indication of end of write. Write cycle endurance is 10,000 Erase/Write cycles with a data retention time of 100 years. The device may be screened in accordance with MIL-STD-883.

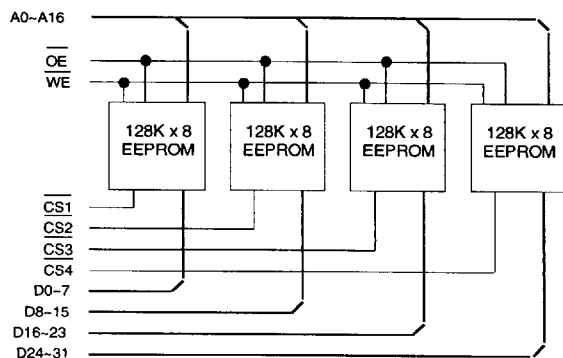
4,194,304 bit CMOS EEPROM Module

Features

- Access Times of 120/150/170/200 ns.
- User Configurable as 8 / 16 / 32 bit wide output.
- Operating Power 445/830/1600 mW (max).
- JEDEC 68 'J' Ceramic Surface Mount Substrate, available in two pinouts : Single WE, WE1~4 is version A.
- Byte and Page Write (128 Bytes) in 5ms typical with DATA Polling and Toggle bit indication of end of Write.
- Hardware and Software Data Protection.
- Endurance of 10⁴ Erase/Write Cycles and Data Retention Time of 100 years.
- Can be processed in accordance with MIL-STD-883.

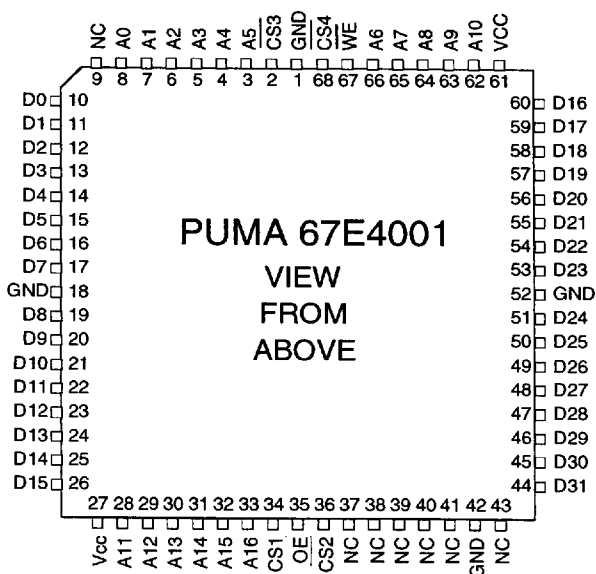
Block Diagram

(see page 11 for Block Diagram of option /A)



Pin Definition

(see page 11 for option /A Pinout)



Pin Functions

A0~16 Address Inputs
CS1~4 Chip Select
WE Write Enable (**WE1~4** on version A)
V_{cc} Power(+5V)

D0~31 Data Inputs/Outputs
OE Output Enable
NC No Connect
GND Ground

DC OPERATING CONDITIONS**Absolute Maximum Ratings ⁽¹⁾**

Operating Temperature	T_{OPR}	-55 to +125	°C
Storage Temperature	T_{STG}	-65 to +150	°C
Input voltages (including N.C. pins) with Respect to GND	V_{IN}	-0.6 to +6.25	V
Output voltages with respect to GND	V_{OUT}	-0.6 to $V_{CC}+0.6$	V

Notes: (1) Stresses above those listed may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Recommended Operating Conditions

		<i>min</i>	<i>typ</i>	<i>max</i>	
DC Power Supply Voltage	V_{CC}	4.5	5.0	5.5	V
Input Low Voltage	V_{IL}	-1.0	.	0.8	V
Input High Voltage	V_{IH}	2.0	.	$V_{CC}+1$	V
Operating Temp Range	T_A	0	.	70	°C
	T_{AI}	-40	.	85	°C (I Suffix)
	T_{AM}	-55	.	125	°C (M, MB Suffix)

DC Electrical Characteristics ($T_A = -55^\circ\text{C}$ to $+125^\circ\text{C}$, $V_{CC} = 5\text{V} \pm 10\%$)

Parameter	Symbol	Test Condition	<i>min</i>	<i>max</i>	Unit
Input Leakage Current	I_{L1}	$V_{IN} = \text{GND to } V_{CC}+1$	.	40	μA
Output Leakage Current	32 bit I_{LO}	$V_{I/O} = \text{GND to } V_{CC}$, $\overline{\text{CS}}^{(1)} = V_{IH}$	.	40	μA
Operating Supply Current	32 bit I_{CC32}	$\overline{\text{CS}}^{(1)} = \overline{\text{OE}} = V_{IL}$, $\overline{\text{WE}} = V_{IH}$, $I_{OUT} = 0\text{mA}$, $f = 5\text{MHz}^{(2)}$	.	320	mA
	16 bit I_{CC16}	As above	.	166	mA
	8 bit I_{CC8}	As above	.	89	mA
Standby Supply Current	TTL levels I_{SB1}	$\overline{\text{CS}}^{(1)} = 2.0\text{V to } V_{CC}+1\text{V}$	.	12	mA
	CMOS levels I_{SB2}	$\overline{\text{CS}}^{(1)} = V_{CC}-0.3\text{V to } V_{CC}+1\text{V}$	.	1.2	mA
Output Low Voltage	V_{OL}	$I_{OL} = 2.1\text{mA}$.	.	0.45	V
Output High Voltage	V_{OH}	$I_{OH} = -400\mu\text{A}$.	2.4	.	V

Notes (1) $\overline{\text{CS}}$ above are accessed through $\overline{\text{CS}}1\sim4$. These inputs must be operated simultaneously for 32 bit operation, in pairs in 16 bit mode and singly for 8 bit mode.

(2) Also for $\overline{\text{WE}}1\sim4$ on the PUMA67E4001A version. Additionally, $\overline{\text{WE}}1\sim4$ are accessed as in note (1) above.

Capacitance ($T_A = 25^\circ\text{C}$, $f = 1\text{MHz}$) Note: These parameters are calculated, not measured.

Parameter	Symbol	Test Condition	<i>typ</i>	<i>max</i>	Unit
Input Capacitance	$\overline{\text{CS}}1\sim4$, $\overline{\text{WE}}1\sim4^{(1)}$	C_{IN1} $V_{IN} = 0\text{V}$	.	20	pF
	Other Inputs	C_{IN2} $V_{IN} = 0\text{V}$	.	22	pF
Output Capacitance	C_{OUT}	$V_{OUT} = 0\text{V}$	.	22	pF

Notes: (1) On the PUMA67E4001A version only.

AC OPERATING CONDITIONS**Read Cycle**

Parameter	Symbol	12		15		17		20		Unit
		min	max	min	max	min	max	min	max	
Read Cycle Time	t_{RC}	120	-	150	-	170	-	200	-	ns
Address Access Time	t_{AA}	-	120	-	150	-	170	-	200	ns
Chip Select Access Time	t_{CS}	-	120	-	150	-	170	-	200	ns
Output Enable Access Time	t_{OE}	0	60	0	70	0	70	0	80	ns
Chip Select High to High Z Output(1)	t_{HZ}	0	50	0	50	0	50	0	50	ns
Output Enable High to High Z Output(1)	t_{OHZ}	0	50	0	50	0	50	0	50	ns
Chip Select Low to Active Output(1)	t_{LZ}	0	-	0	-	0	-	0	-	ns
Output Enable Low to Active Output(1)	t_{OLZ}	0	-	0	-	0	-	0	-	ns
Output Hold from Address Change	t_{OH}	0	-	0	-	0	-	0	-	ns

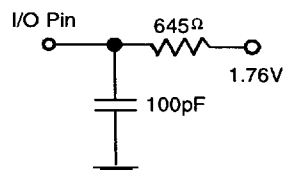
Notes:(1) t_{HZ} max. and t_{OLZ} max. are measured with $C_L = 5pF$, from the point when Chip Select or Output Enable return high (whichever occurs first) to the time when the outputs are no longer driven. t_{HZ} and t_{OHZ} are shown for reference only: they are characterized and not tested.

Write Cycle

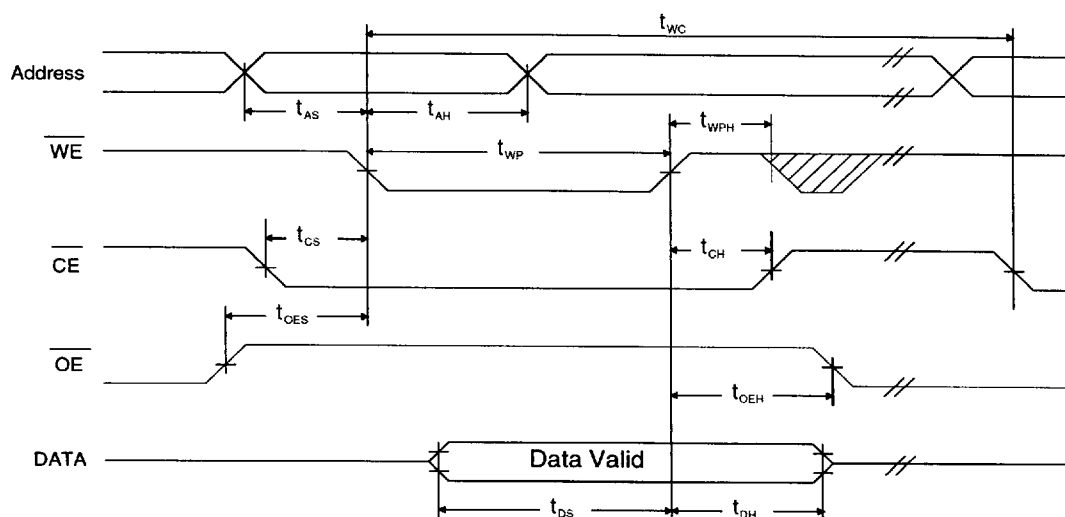
Parameter	Symbol	min	typ	max	Unit
Write Cycle Time	t_{WC}	-	-	10	ms
Address Set-up Time	t_{AS}	0	-	-	ns
Address Hold Time	t_{AH}	50	-	-	ns
Output Enable Set-up Time	t_{OES}	0	-	-	ns
Output Enable Hold Time	t_{OEh}	0	-	-	ns
Chip Select Set-up Time	t_{CS}	0	-	-	ns
Chip Select Hold Time	t_{CH}	0	-	-	ns
Write Pulse Width	t_{WP}	100	-	-	ns
Write Enable High Recovery	t_{WPH}	50	-	-	ns
Data Set-up Time	t_{DS}	50	-	-	ns
Data Hold Time	t_{DH}	0	-	-	ns
Byte Load Cycle	t_{BLC}	-	-	150	μs

AC Test Conditions**Output Test Load**

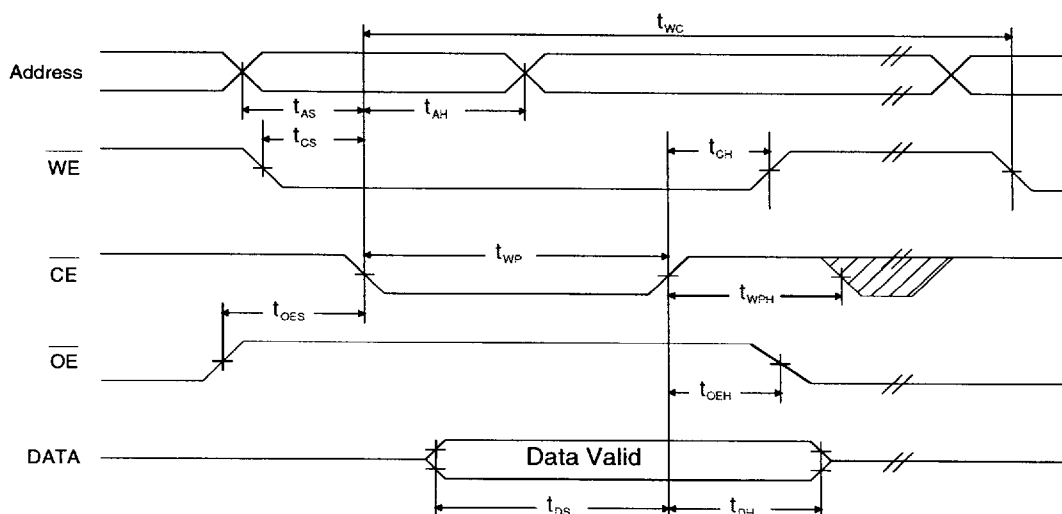
- * Input pulse levels: 0V to 3.0V
- * Input rise and fall times: 10ns
- * Input and Output timing reference levels: 1.5V
- * Output load: 1 TTL gate + 100pF
- * $V_{CC} = 5V \pm 10\%$



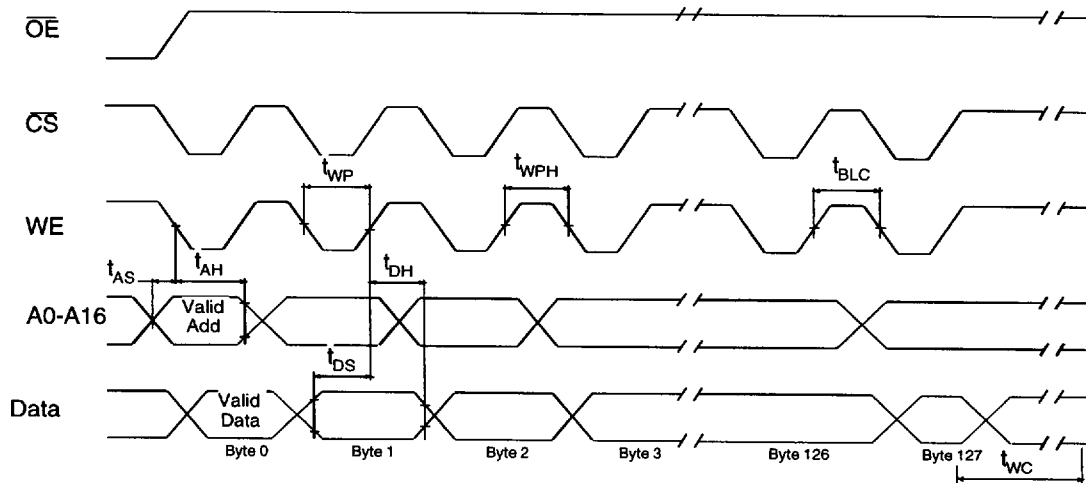
AC Write Waveform - WE Controlled



AC Write Waveform - $\overline{CS}$ Controlled

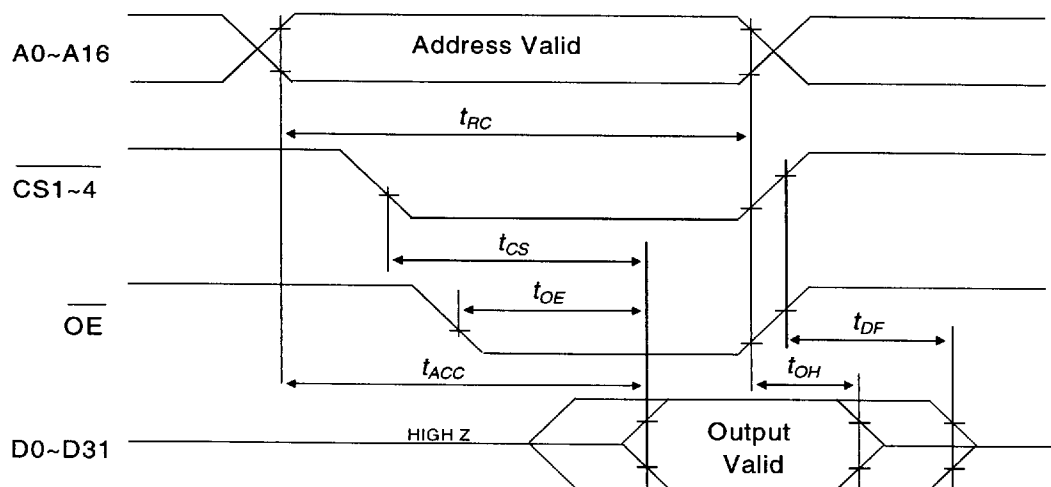


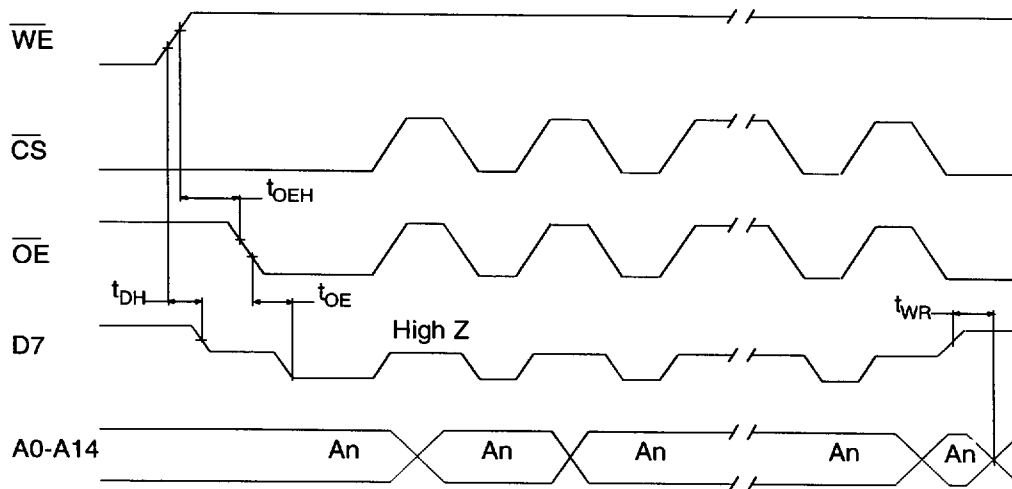
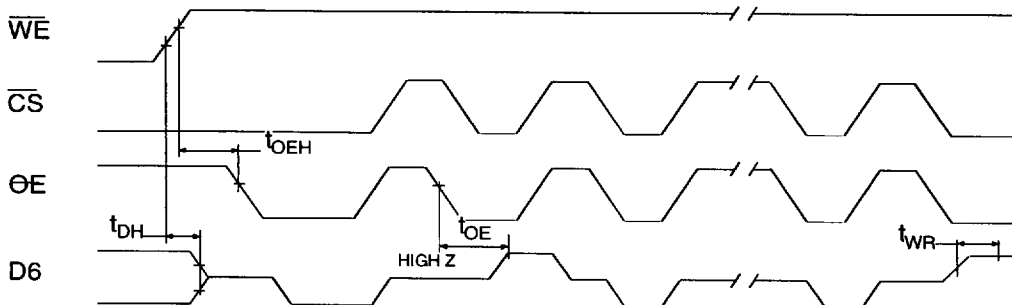
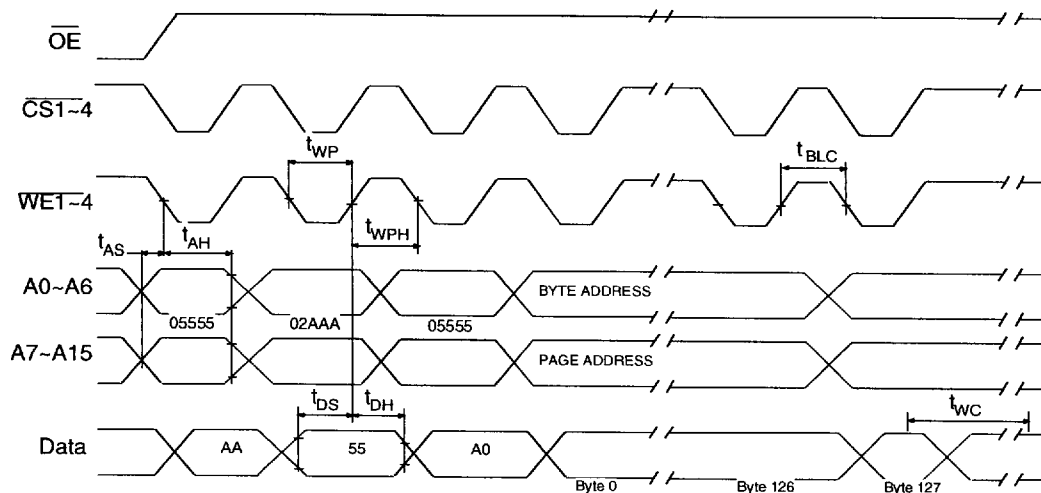
Page Mode Write Waveform



Note: A8 through A16 must specify the page address during each high to low transition of Write Enable (or Chip select). Output Enable must be high only when Write Enable and Chip Select are both low.

Read Cycle Timing Waveform



DATA Polling Waveform**Toggle Bit Waveform****Software Protected Write Waveform**

Device Operation

The following description deals with the PUMA 67E4001 device, with the references to $\overline{WE}$ meaning $\overline{WE1\sim4}$ on the PUMA 67E4001A part.

Read

The PUMA 67E4001 read operations are initiated by both Output Enable and Chip Select LOW. The read operation is terminated by either Chip Select or Output Enable returning HIGH. This 2-line control architecture eliminates bus contention in a system environment. The data bus will be in a high impedance state when either Output Enable or Chip Select is HIGH.

Write

Write operations are initiated when both Chip Select and Write Enable are LOW and Output Enable is HIGH. The PUMA 67E4001 supports both a Chip Select and Write Enable controlled write cycle. That is, the address is latched by the falling edge of either Chip Select or Write Enable, whichever occurs last. Similarly, the data is latched internally by the rising edge of either Chip Select or Write Enable, whichever occurs first. A byte write operation, once initiated, will automatically continue to completion, typically within 5 ms.

Page Mode Write

The page write feature of the PUMA 67E4001 allows the entire memory to be written in 5 seconds. Page Write allows 128 bytes of data to be written prior to the internal programming cycle. The host can fetch data from another location within the system during a page write operation (change the source address), but the page address (A8 through A16) for each subsequent valid write cycle to the part during this operation must be the same as the initial page address.

The page write mode can be initiated during any write operation. Following the initial byte write cycle, the host can write up to 128 bytes in the same manner as the first byte written. Each successive byte load cycle, started by the Write Enable HIGH to LOW transition, must begin within 150 μ s of the falling edge of the preceding Write Enable. If a subsequent Write Enable HIGH to LOW transition is not detected within 150 μ s, the internal automatic programming cycle will commence.

DATA Polling

The PUMA 67E4001 features DATA Polling to indicate if the write cycle is completed. During the internal programming cycle, any attempt to read the last byte written will produce the complement of that data on D7. Once the programming is complete, D7 will reflect the true data. Note: If the PUMA 67E4001 is in a protected state and an illegal write operation is attempted DATA Polling will not operate.

TOGGLE bit

In addition to DATA polling, another method is provided to determine the end of a Write Cycle. During a write operation successive attempts to read data will result in D6 toggling between 1 and 0. Once a write is complete, this toggling will stop and valid data will be read.

Hardware Data Protection

The PUMA 67E4001 provides three hardware features to protect nonvolatile data from inadvertent writes.

- Noise Protection - A Write Enable pulse less than 15 ns will not initiate a write cycle.
- Default V_{CC} Sense - All functions are inhibited when $V_{CC} < 3.6$ V.
- Write Inhibit - Holding either Output Enable LOW, Write Enable HIGH or Chip Select HIGH will prevent an inadvertent write cycle during power on or power off, maintaining data integrity.

Software Data Protection

The PUMA67E4001 can be automatically protected during power-up and power-down without the need for external circuits by employing the software data protect feature. The internal software data protection circuit is enabled after the first write operation utilizing the software algorithm. This circuit is nonvolatile and will remain set for the life of the device unless the reset command is issued.

Once the software protection is enabled, the PUMA67E4001 is also protected against inadvertent and accidental writes in that, the software algorithm must be issued prior to writing additional data to the device.

Operating Modes

The table below shows the logic inputs required to control the operation of the PUMA67E4001.

MODE	$\overline{CS}$	OE	WE	OUTPUTS
Read	0	0	1	Data Out
Write	0	1	0	Data in
Standby	1	X	X	Floating
Write Inhibit	X	X	1	
	X	0	X	

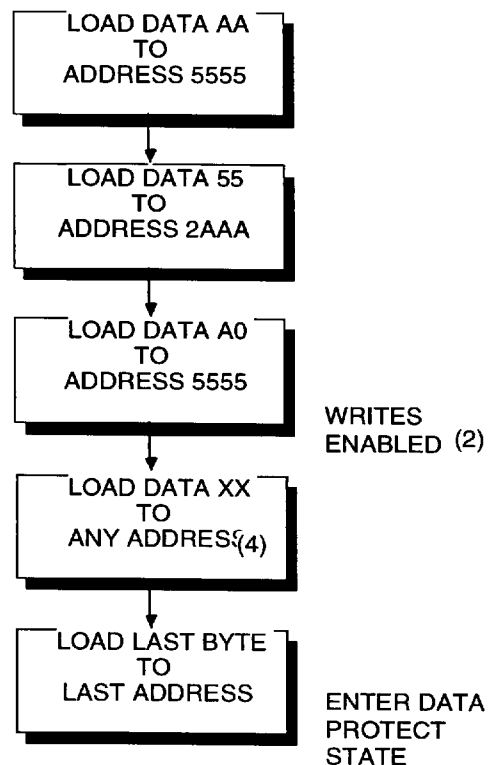
0 = V_{IL} : 1 = V_{IH} : X = V_{IH} or V_{IL}

Software Algorithms

Selecting the software data protection mode requires the host system to precede datawrite operations by a series of three write operations to three specific addresses. The three byte sequence opens the page write window enabling the host to write from 1 to 128 bytes of data. Once the page load cycle has been completed, the device will automatically be returned to the data protected state.

Software Data Protection Algorithm

Regardless of whether the device has been protected or not, once the software data protection algorithm is used and the data is written, the PUMA 67E4001 will automatically disable further writes unless another command is issued to cancel it. If no further commands are issued the PUMA 67E4001 will be write protected during power-down and any subsequent power-up.



Notes:

(1) Data Format I/O7-I/O0 (Hex);

Once initiated, this sequence of write operations should not be interrupted.

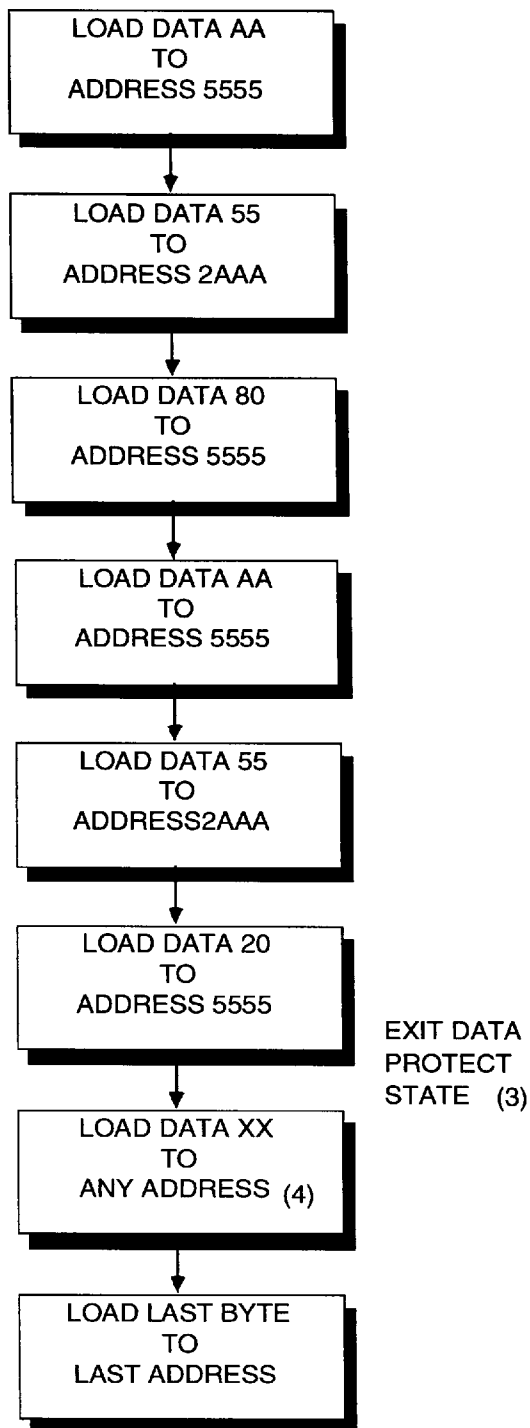
(2) Enable Write Protect state will be initiated at end of write even if no other data is loaded.

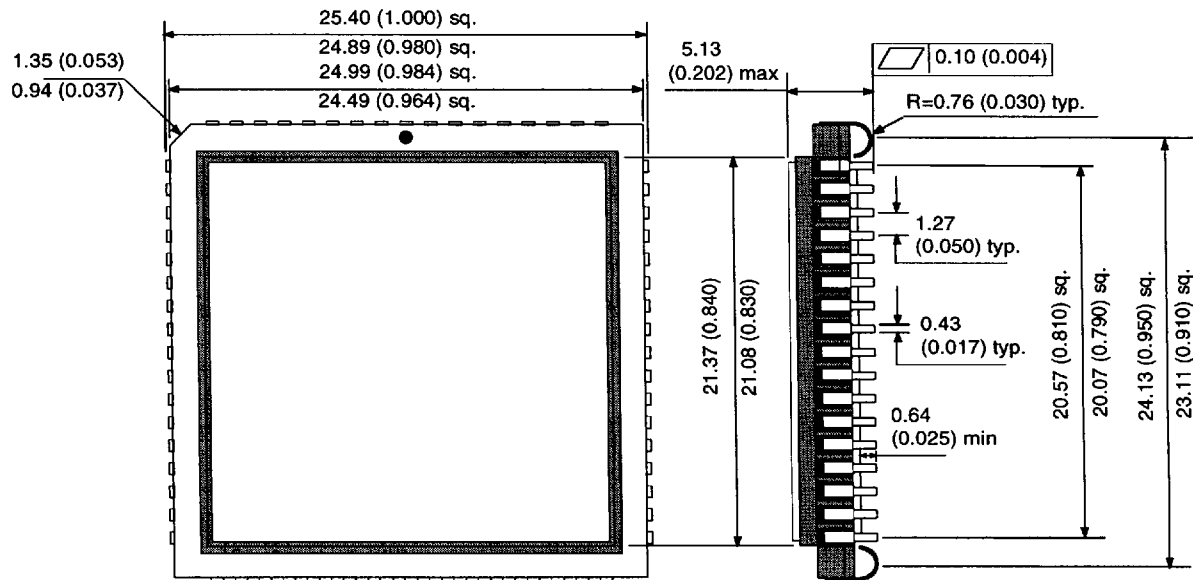
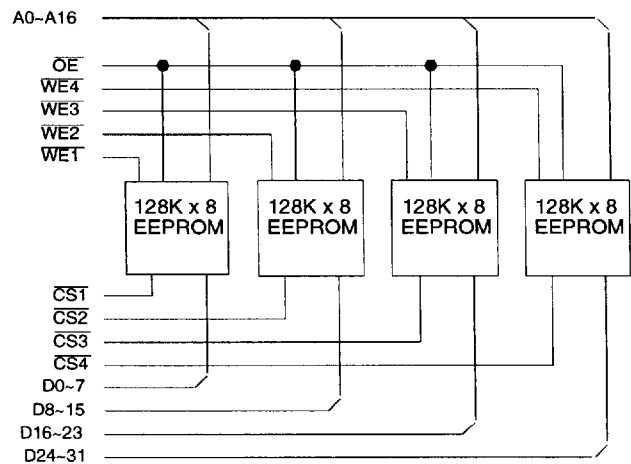
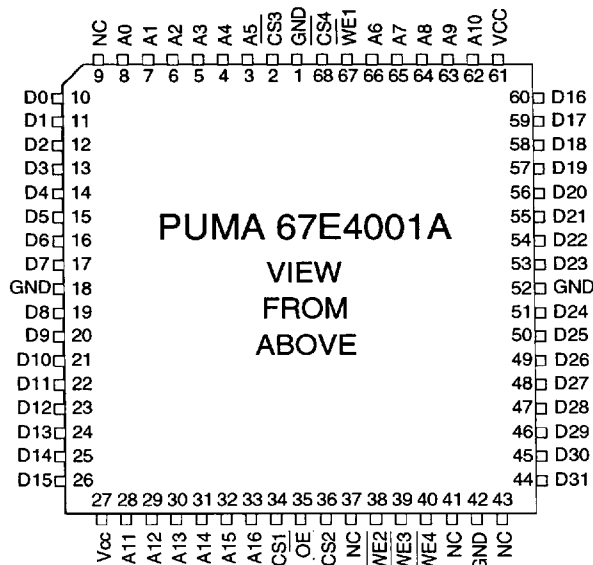
(3) Disable Write Protect state will be initiated at end of write period even if no other data is loaded.

(4) 1 to 128 bytes of data may be loaded.

Software Data Protect Disable

In the event the user wants to deactivate the software data protection feature for testing or reprogramming in an E²PROM programmer. The following six step algorithm will reset the internal protection circuit. After t_{WC} , the PUMA 67E4001 will be in standard operating mode.



Package Details Dimensions in inches. Lead finish gold.

Pin Definition version /A
Block Diagram version /A


Military Screening Procedure

MultiChip Screening Flow for high reliability product is in accordance with Mil-883 method 5004 .

MB MULTICHIP MODULE SCREENING FLOW

Visual and Mechanical		
Internal visual	2010 Condition B or manufacturers equivalent	100%
Temperature cycle	1010 Condition C (10 Cycles, -65°C to +150°C)	100%
Constant acceleration	2001 Condition B (Y1 & Y2) (10,000g)	100%
Endurance		
Write Cycle endurance and Data Retention performance	As per Internal Specification.	
Burn-In		
Pre-Burn-in electrical	Per applicable device specifications at $T_A = +25^\circ\text{C}$	100%
Burn-in	$T_A = +125^\circ\text{C}$, 160hrs min	100%
Final Electrical Tests	Per applicable Device Specification	
Static(DC)	a) @ $T_A = +25^\circ\text{C}$ and power supply extremes	100%
	b) @ temperature and power supply extremes	100%
Functional	a) @ $T_A = +25^\circ\text{C}$ and power supply extremes	100%
	b) @ temperature and power supply extremes	100%
Switching(AC)	a) @ $T_A = +25^\circ\text{C}$ and power supply extremes	100%
	b) @ temperature and power supply extremes	100%
Percent Defective allowable (PDA)	Calculated at post-burn-in at $T_A = +25^\circ\text{C}$	10%
Hermeticity	1014	
Fine	Condition A	100%
Gross	Condition C	100%
Quality Conformance	Per Applicable Device Specification	Sample
External Visual	2009 Per vendor or customer specification	100%

Ordering Information

PUMA 67E4001AMB-15E

